



US00D395242S

United States Patent [19]

Yamakoshi et al.

[11] Patent Number: Des. 395,242

[45] Date of Patent: **Jun. 16, 1998

[54] ANALOG MULTI-METER

D. 366,432 1/1996 Wisley et al. D10/78

[75] Inventors: **Hideto Yamakoshi; Kouichi Tanaka; Yoshio Yanagawa.** all of Ueda, Japan

Primary Examiner—Antoine Duval Davis
Attorney, Agent, or Firm—Kanesaka & Takeuchi

[73] Assignee: **Hioki Denki Kabushiki Kaisha.** Ueda, Japan

[57] CLAIM

[**] Term: 14 Years

The ornamental design for an analog multi-meter, as shown and described.

[21] Appl. No.: 67,663

DESCRIPTION

[22] Filed: Mar. 6, 1997

[30] Foreign Application Priority Data

Jan. 20, 1997 [JP] Japan 9-1124

FIG. 1 is a perspective view of an analog multi-meter, with the scale omitted, showing our new design;

[51] LOC (6) Cl. 10-04

FIG. 2 is a front view thereof;

[52] U.S. Cl. D10/78

FIG. 3 is a right side view thereof;

[58] Field of Search D10/78; 324/110, 324/115; 340/635, 686, 687, 693

FIG. 4 is a left side view thereof;

FIG. 5 is a rear view thereof;

FIG. 6 is a top plan view thereof; and,

FIG. 7 is a bottom view thereof.

[56] References Cited

U.S. PATENT DOCUMENTS

D. 300,306 3/1989 Arnoux et al. D10/78

1 Claim, 4 Drawing Sheets

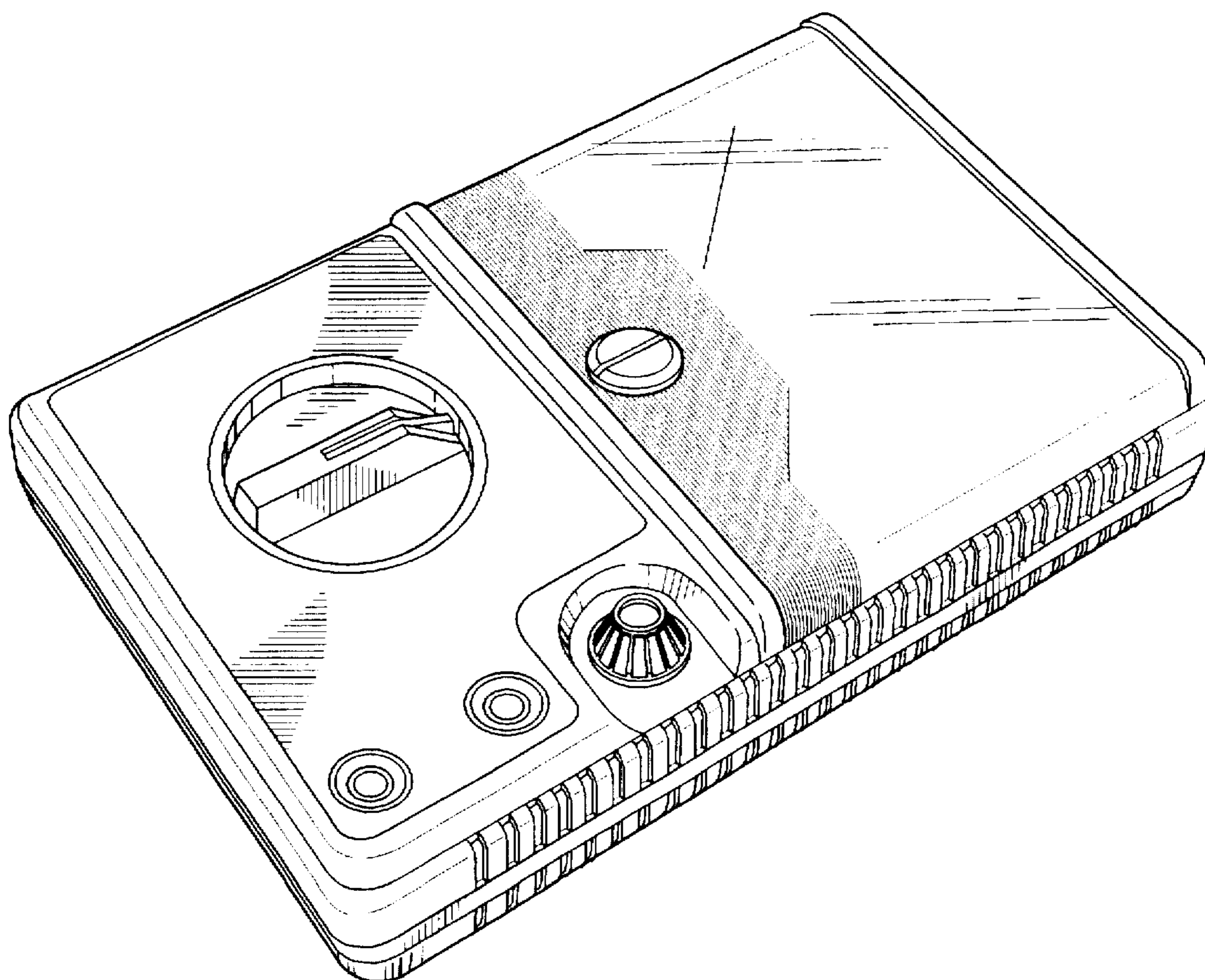


FIG. 1

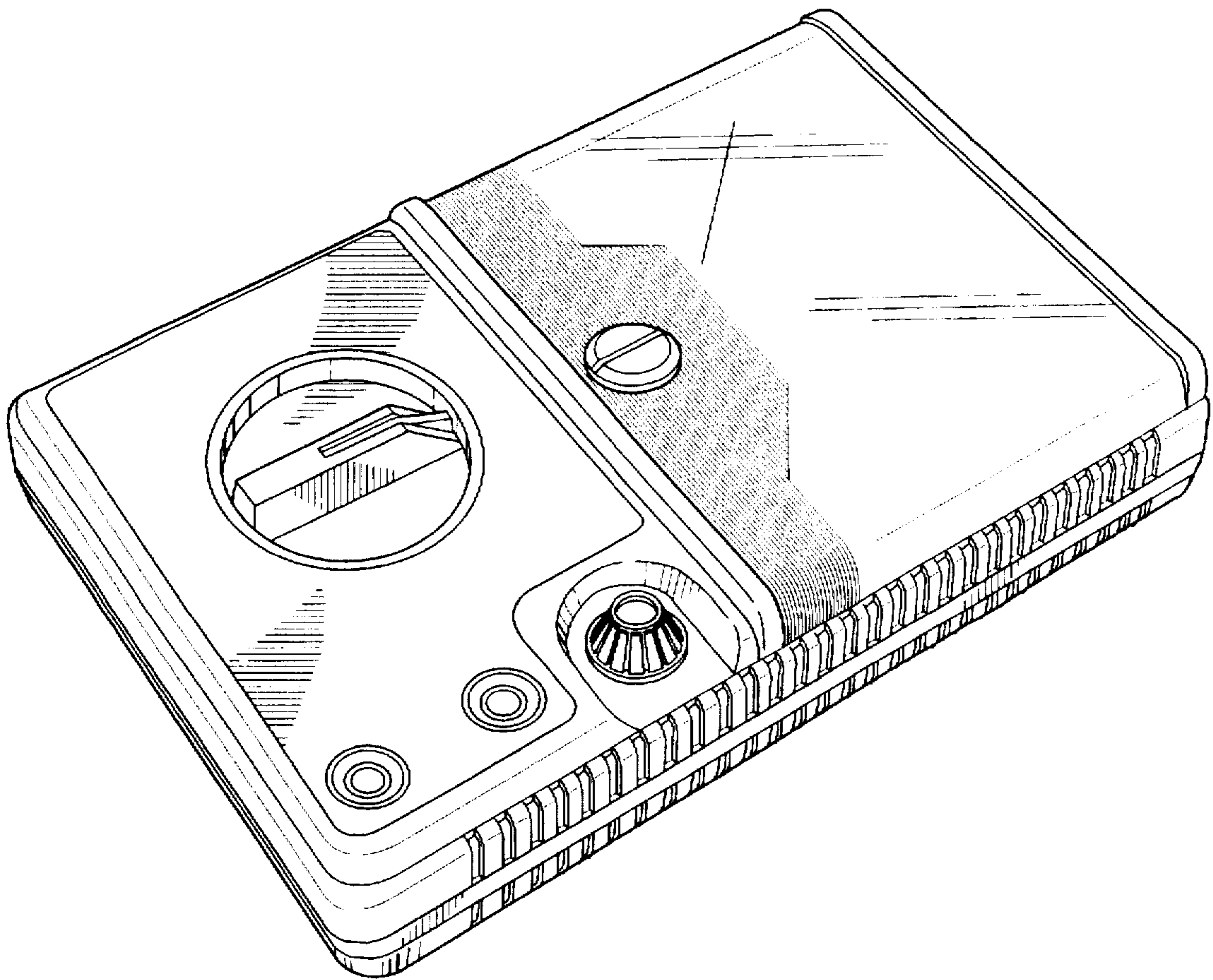


FIG. 2

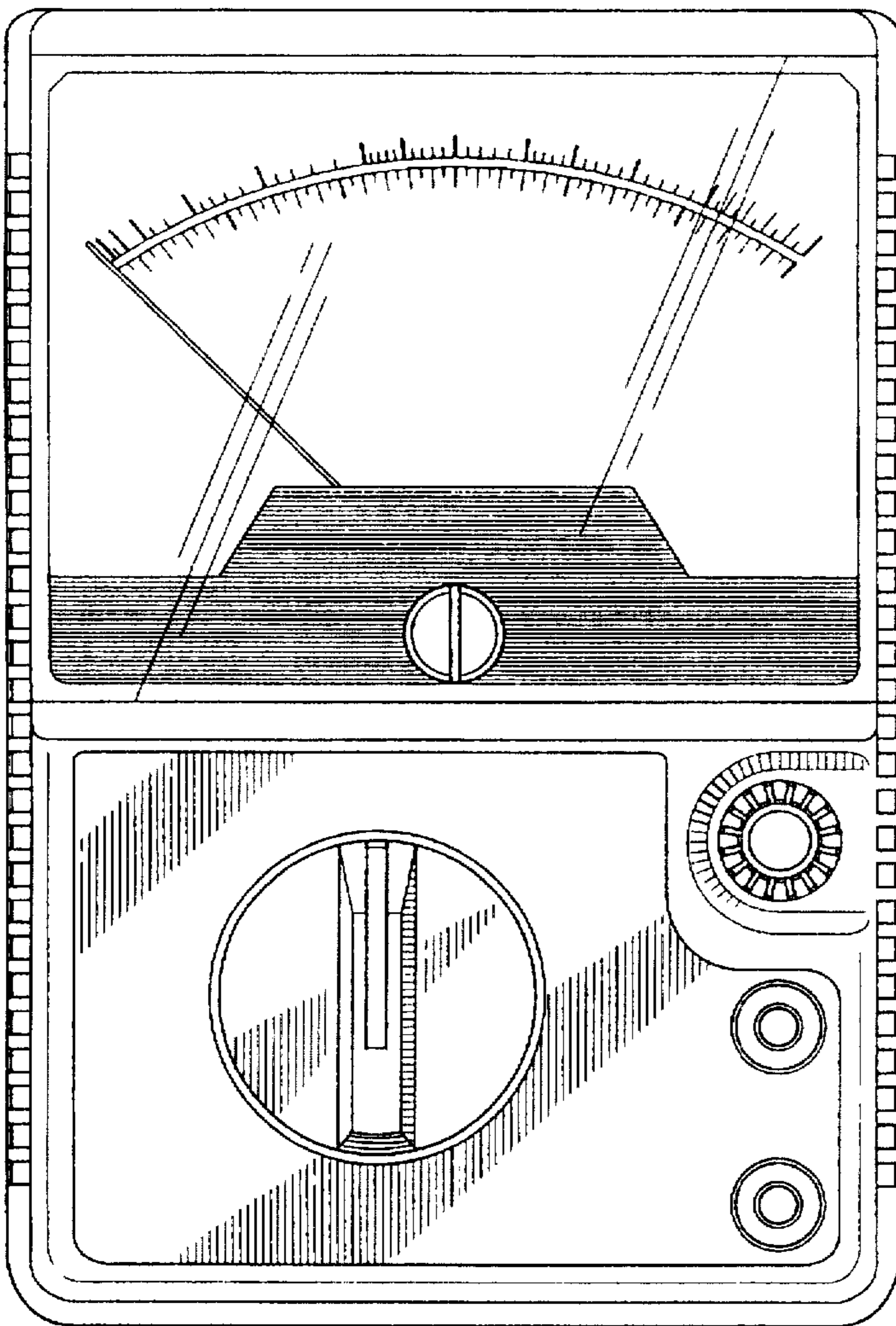


FIG. 3

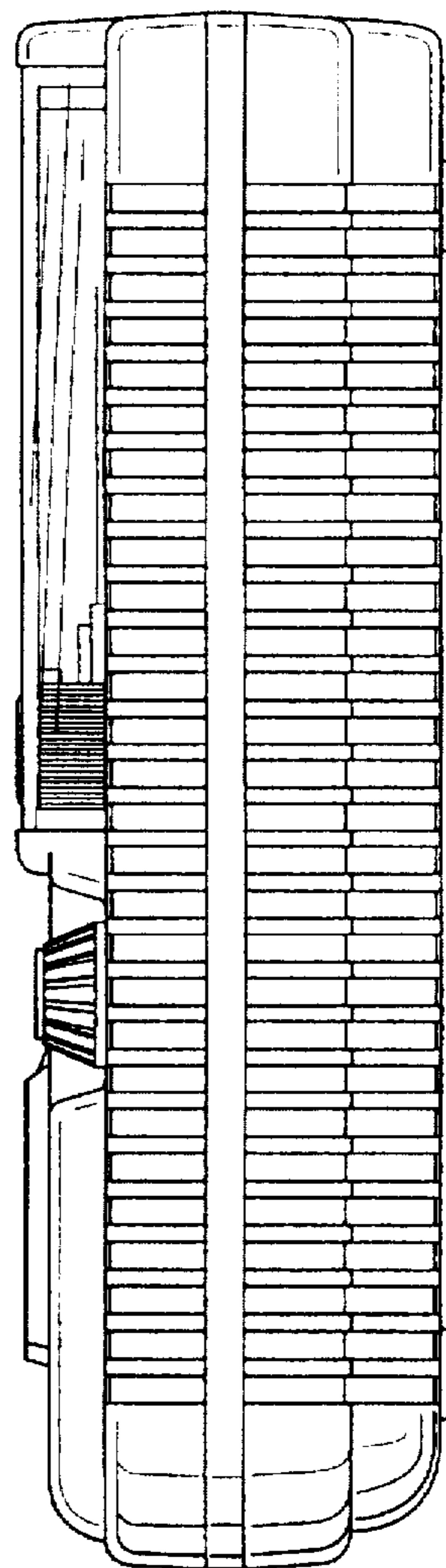


FIG. 4

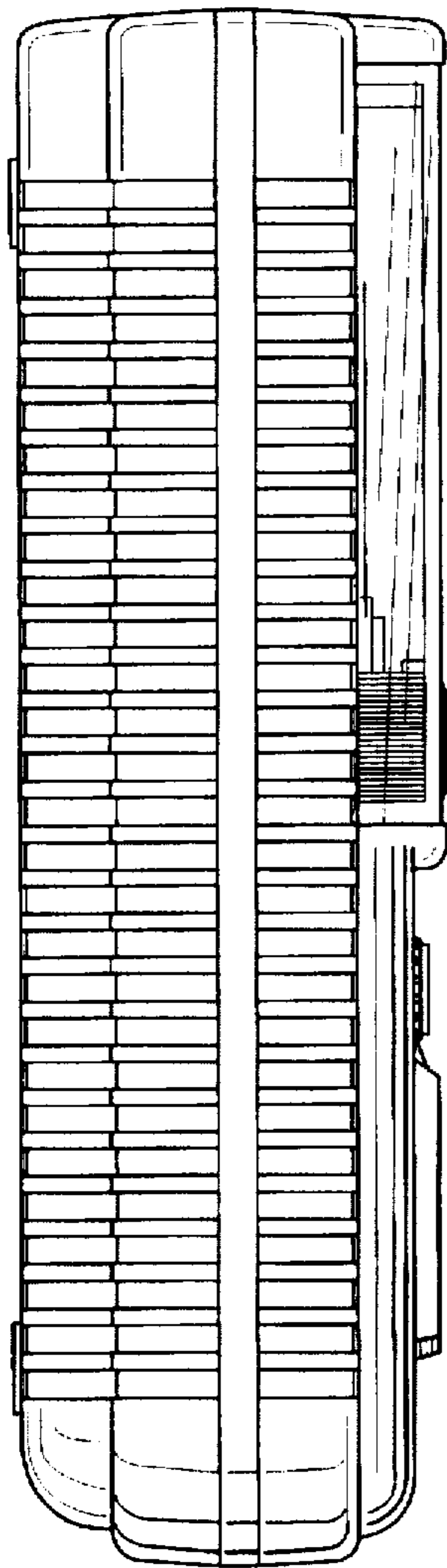


FIG. 5

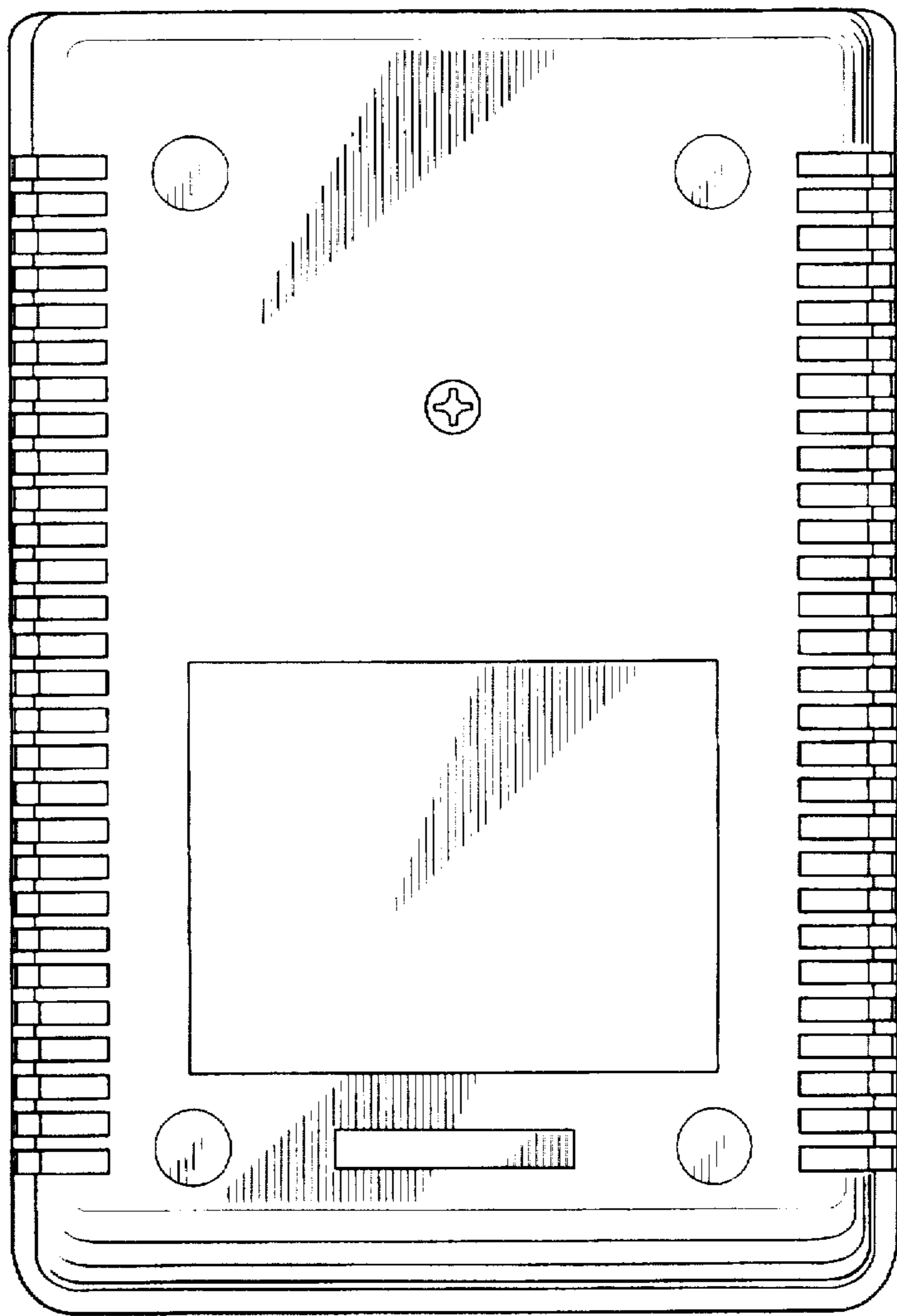


FIG. 6

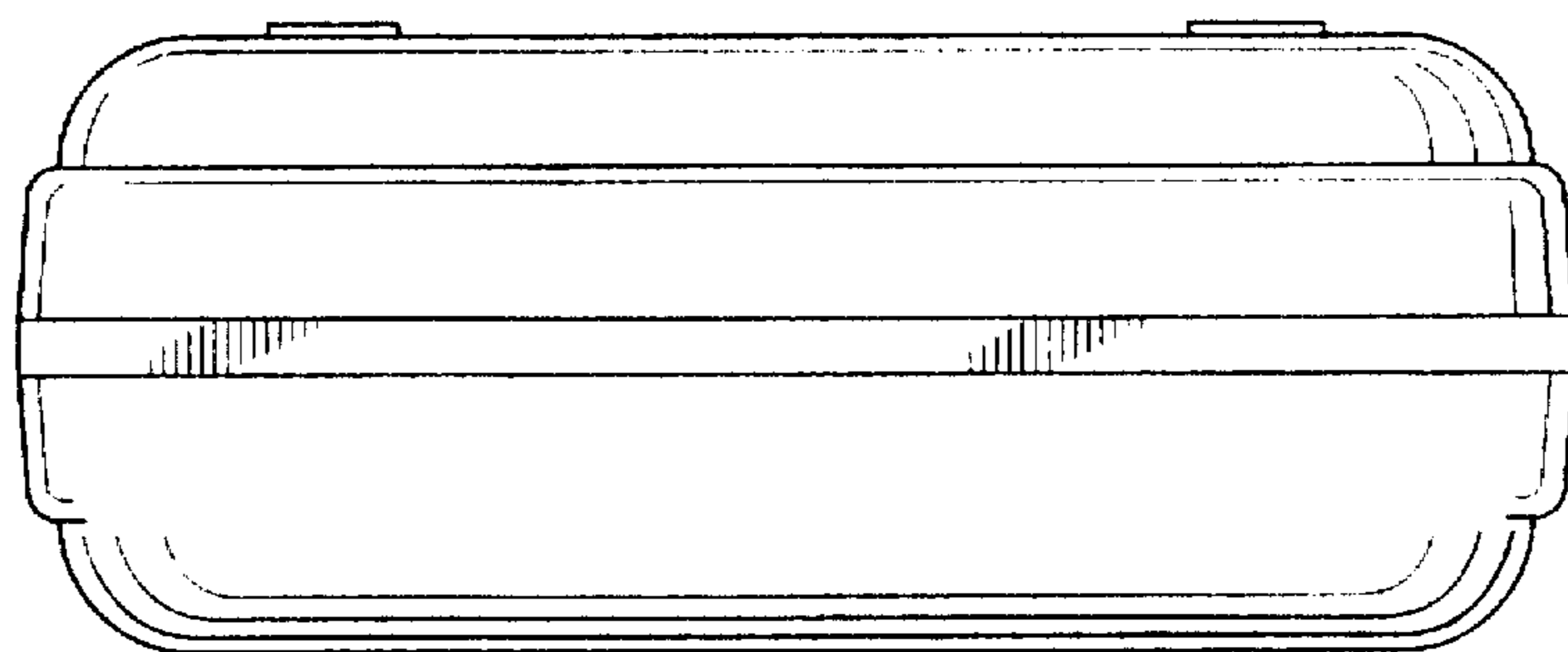


FIG. 7

